

Annual International DIC Society Conference and SEM Fall Conference November 7 – 10, 2016 in Philadelphia, PA

<http://idics.org/idics-2016>

General Call

The International Digital Image Correlation Society (iDICS) is inviting your participation in its annual conference in Philadelphia, PA. We welcome you to join this new society aimed at inspiring their members to continually improve their application and development of image correlation methods. The board encourages you to join in presenting and participating in the active committees to help guide DIC into the future.

iDICS Board
Michael Sutton
(Pres.)
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Inverse Methods for Full-field Measurements (Track 1)

In collaboration with the Society for Experimental Mechanics (SEM)

Organizer: Prof. Fabrice Pierron

We invite you to submit papers to an exciting area of research in material property identification using full-field methods: VFM, inverse FE, etc. This track organized by Prof. Fabrice Pierron will be co-organized as the annual fall conference of SEM.

DIC for Biological Applications (Track 2)

Organizer: Prof. Christian Franck

DIC is making great in-roads in biological measurements. The flexibility of the technique to be used in a variety of imaging modalities makes it an important tool, including: CT, confocal microscopy, and traditional imaging. Submit your new research using DIC in the Biosciences.

Industrial Applications for DIC (Track 3)

Organizer: DIC Vendors

Applications for DIC in industrial settings are wide ranging and increasingly important. Come share your particular applications with a broad audience, show off your work and collaborate on DIC best practices.

Important Dates

Abstract submission extended until Aug. 5, 2016

Send to info@idics.org

Paper due Aug. 15th

Early Registration until Sept. 1

DoubleTree by Hilton

Hotel Philadelphia Center City

237 South Broad Street, Philadelphia, PA



Mission: Extend – Train – Standardize – Improve

Extending the Frontiers: Training the next Generation:

Standardizing for Industry: Improving our Practice

General Call

The International Digital Image Correlation Society is soliciting papers on the application and development of DIC. Submit your paper to the general call, or any of the following organized sessions.

Organized Sessions

- Novel DIC Applications – *Session Chairs: Michel Coret (Ecole Centrale de Nantes/GeM) and David Dawicke (AS&M/NASA Langley)*
- Outdoor and Large Scale Testing – *Session Chairs: Nate Gardner (AS&M/NASA LaRC) and Tim Miller (Sandia)*
- Uncertainty Quantification for DIC – *Session Chair: Benoît Blaysat (Blaise Pascal University/Institut Pascal) and Bertrand Wattrisse (Université de Montpellier/LMGC)*
- Modal Testing with DIC – *Session Chairs: Chris Niezrecki (Umass Lowell) and Tim Beberniss (AFRL)*
- DIC for Material Characterization – *Session Chair: Helena Jin (Sandia)*
- Algorithms and Computational Methods – *Session Chairs: Bing Pan (Beijing Univ. of A&A), Dan Turner (Sandia) and Julien Réthoré (CNRS/GeM)*
- Global DIC – *Session Chair: Benoît Blaysat (Blaise Pascal University/Institut Pascal) and Jean-Charles Passieux (INSA Toulouse/Clément Ader Institute)*
- High and Ultra-High Speed DIC – *Session Chair: Phillip Reu (Sandia)*
- Digital Volume Correlation (DVC) – *Session Chairs: Mike Czabaj (Univ. of Utah), Julien Réthoré (CNRS/GeM), Helena Jin (Sandia) and Yannick Pannier (ISAE-ENSMA/Pprime Institute)*
- DIC for Civil Engineering – *Session Chair: Devon Harris (Univ. Virginia) and Evelyne Toussaint (Blaise Pascal University/Institut Pascal)*
- DIC for Sheet Metal Forming – *Session Chair: Lianxiang Yang (Oakland Univ.) and Mark Iadicola (NIST)*
- Other open topics: DIC in Education, DIC Standardization, Global Methods

Monday Courses (November 7)

- Practical Considerations for Quantitative DIC Measurements – *Instructor: Pascal Lava (MatchID)*
- How to Pattern...Everything– *Instructor: Tim Schmidt (Trilion/GOM)*
- Uncertainty Quantification/Standardization for DIC – *Instructors: Phillip Reu (Sandia) and Mark Iadicola (NIST)*

Abstract Submission: Info@idics.org

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Committee Meetings

- Training & Certification
- Standardization & UQ
- DIC Challenge
- Applications
- Meeting organization

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